


<b>Search Notes</b>  	<b>Application/Control No.</b>  10529691	<b>Applicant(s)/Patent Under Reexamination</b>  HWANG ET AL.
	<b>Examiner</b>  David Ton	<b>Art Unit</b>  2117

SEARCHED			
Class	Subclass	Date	Examiner
707	205	3/30/07	DT
369	47.14	3/30/07	DT
369	53.1	3/30/07	DT
714	8	3/30/07	DT
714	723	3/31/07	DT
714	710	3/31/07	DT
714	710	9/16/07	DT
714	54	9/16/07	DT
714	710	6/8/08	DT
714	54	6/8/08	DT

SEARCH NOTES		
Search Notes	Date	Examiner
WEST, JPAB, TDBD, DWPI searches	3/30/07	
WEST, IEEE searches	3/31/07	
WEST searches	9/16/07	
EAST, JPO, DERWENT searches	6/8/08	

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
714	710	6/8/08	DT
714	54	6/8/08	DT